

FRAUNHOFER INSTITUTE FOR RELIABILITY AND MICROINTEGRATION IZM

Early Access MPFOWLP Run available mid 2019 For more information please contact us!

CONTACT

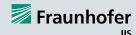
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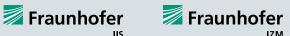
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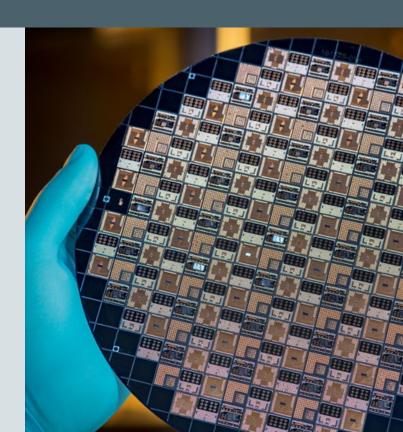
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MULTI-PROJECT FAN-OUT WAFER LEVEL PACKAGING FOR EUROPRACTICE



MPFOWL PACKAGE SPECIFICATION

• Die delivery: WafflePack, wafer, wheel

• Die size: 1.5 – 7 mm edge length

• Die thickness: 200 – 300 μm

Package thickness: 450 µm

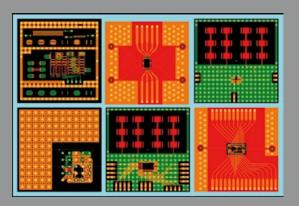
 Package size: 10x10 mm², smaller package size possible with extra effort

• Metal layers: 2

• Integration of e.g. antennas and passive structures in RDL

Pin-out: BGA
 Pitch: 500 µm
 Ball size: 300 µm
 Solder: SnAgCu

• Defined packaging materials

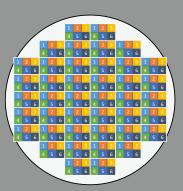


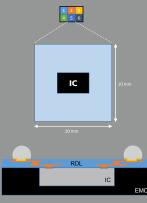
DESIGN RULES & MATERIALS

Multi-project wafer processing is an established approach in semiconductor manufacturing for fast and low cost prototyping. This idea is now transferred to fan-out wafer level packaging. Here dies from different sources or different technologies with varying thickness and size can be handled and packaged with one integration technology. This offers a path to a well adopted technology, especially for RF applications.

LOW VOLUME PROTOTYPING MULTI PROJECT FAN-OUT WAFER LEVEL PACKAGING

FOWLP Reticle





Multi Project Fan-out Wafer

FOWLP Package